



78470PCW
Customer No. 01333

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Robert M. Guidash

IMPROVED LINEARITY AND
DYNAMIC RANGE FOR
COMPLEMENTARY METAL OXIDE
SEMICONDUCTOR ACTIVE PIXEL
IMAGE SENSORS

Serial No. US 09/750,745

Filed 29 December 2000

Commissioner for Patents
Washington, D.C. 20231

Sir:

Group Art Unit: 2877

Examiner: Nguyen, Tu T.

I hereby certify that this correspondence is being deposited today with the
United States Postal Service as first class mail in an envelope addressed to
Commissioner for Patents, Washington, D.C. 20231.

Lois A. Massar

Date

DECLARATION UNDER 37 CFR 1.132

Robert M. Guidash declares that he is the inventor of the subject application: that he conceived his invention in this country on November 14, 1997 which is long prior to Aug. 16, 1999 (hereinafter the effective date); that he realized his work as being inventive on May 28, 1998; that he submitted an invention disclosure (enclosed herewith) on October 20, 1998; that it was approved by management on October 23, 1998; that to the best of his knowledge, Jim Leimbach, the Eastman Kodak Attorney (no longer employed with Eastman Kodak Company), diligently attempted to progress through his docket to start working on the subject invention; that, to the best of his knowledge, Jim Leimbach realized his docket prevented him from working on it in a desired time; that Jim Leimbach sent the subject application to an outside attorney, Fred Gibbs, on March 7, 2000; that there was numerous correspondence with Fred Gibbs on the subject patent application; that he responded diligently to the correspondence; that, to the best of his knowledge, Fred Gibbs worked substantially continuously on the subject patent application after he received it; and that he does not believe that his invention has been in public prior to his application; and that he has never abandoned the invention.

He further declares that all statements made herein of his own knowledge are true and that all statements made on information and belief are believed to be true; and further that these statements were made with knowledge that willful false statements and the like so made are punishable by fine or imprisonment, or both under Section 1001 of Title 18 of the United States Code, and that such willful false statements may jeopardize the validity of the application or any patent issuing thereon.

Respectfully Submitted,

Robert M. Guidash

INVENTION SUMMARY FOR IP COORDINATOR

SEND TO: IP Coordinator

Instructions: If drawings or other additional information are needed to describe the invention, or if prior art is being submitted, fill out this form, print it, attach copies and mail to your Intellectual Property (IP) Coordinator.

THIS SECTION TO BE COMPLETED BY IP COORDINATOR*

Date Received: 10/22/98Proceed to Patent: ☒ Yes ☐ NoApproved: David N. MichelApproval Date: 10/23/98

IP Coordinator

PRE-FILING EVALUATION

(See IP Subcommittee Guidelines for more detailed rating criteria)

Internal Use (1 = low, 10 = high) 3External Use (1 = low, 10 = high) 8Detectability (.5 = nondetectable, 1.0 = easy to detect) 0.8Docket No.: 78470Docket Date: 9/25/98

Portfolio No. _____

Date Filed in USPTO: _____

*For record keeping, send copies of this form to inventor(s) & attorney.

Earliest date of invention: 11/14/97Date when realized as patentable invention: 5/22/98

Inventors:

R MICHAEL GUIDASHDocumentation: (Notebook No./Page No., Other (e.g., Technical Reports, Memos, Make Sheets, etc.) (1) PC files; MIKE/ACI/TV2DATA/cch.kp.xls(2) Design files; mcd/layout/testm3/cdr-bin(3) Notebook AAS962 pg. 48-50Title of Invention: Improved Linearity for CMOS A/DsSummary of Invention: (See attached documentation)

-Reduces or minimizes ratio of voltage dependent capacitance to total sense node capacitance.
So noise linear across voltage range.

(1) Minimize junction capacitance of floating differential

(2) add voltage independent capacitance to sense nodes

(3) Use omnibic sense configuration

INVENTION SUMMARY FOR IP COORDINATOR (Continued)

Advantages:

• Improved latency
• Lower gain FPN

Limitations:

• None envisioned

Why this invention should be patented:

Higher quality, low cost
Circuits Active Pixel Sensors

Has the invention been reduced to practice? ☒ Yes ☐ No Where, when?

Has the invention been disclosed to the public or offered for sale? ☐ Yes ☒ No
Where, when?

date 5/23/98

AA 5962

Problem: Improved linearity for CMOS Active Pixel Sensors

In CMOS active pixel sensors made in sub- μ m CMOS processes, and scaled supply voltages, it is typical that the capacitance used to convert signal electrons to a voltage has a large voltage coefficient. This is due to the a) large ratio of junction capacitance to interconnect and other gate capacitance components, and b) the change in the junction depletion region as conversion from full well swing is large compared to the nominal depletion region width.

In addition to change to voltage conversion of transfer gated pixels with an isolated charge sense node (i.e. separation from the photodiode), is very high ($\approx 30 \mu\text{V/e-}$ typically), and can limit the saturation signal level.

There are ^{now} ways proposed here to investigate these problems -

(1) Use a common source amplifier as the read out mechanism, rather than a source follower.
(See FIG 1)

In this case the β of the common source amplifier can be made substantially large

David H. Sackett

May 28, 1998

David H. Sackett

problem:

2M56 node

Diagram illustrating a circuit node labeled "2M56 node". The circuit includes a PMOS transistor with gate "TG" and source "FD" (connected to a "PDEC" block). The drain of this PMOS is connected to a node that branches to a PMOS transistor with gate "Pdec" and source "5tt", and also to an NMOS transistor with gate "MI" and source connected to ground. The drain of the NMOS is connected to a "column bus" which has a pull-up PMOS transistor connected to "VDD".

(FIG. 1)

$$C_{in} = (1 - A_v) C_{gd}$$

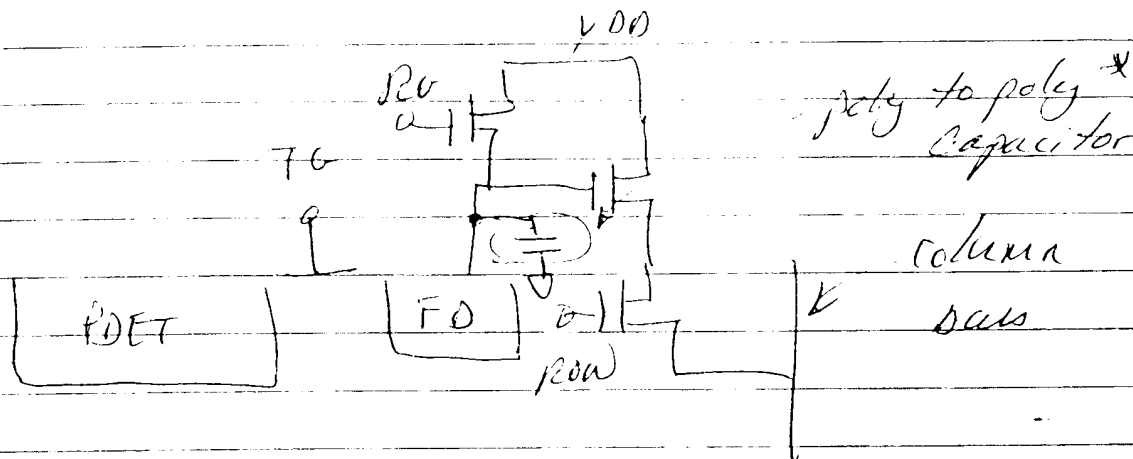
KP 15226-B I.P.S.

Witness:

te 5/28/98

blem: Inwood linearity ...

for the same reasons stated in approach #1.
(see FIG. 2)



poly to poly *
Capacitor

column
bus

* or poly-metal Capacitor, or gate-substrate capac.
or metal-metal etc